

Absolute Maximum Ratings ($T_A = 25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Rating		Unit	
		N Channel	P Channel		
V_{DSS}	Drain-Source Voltage	40	-40	V	
V_{GSS}	Gate-Source Voltage	± 20	± 20		
I_D^*	Continuous Drain Current	$V_{GS}=10\text{V (N)}$	6.5	-5	A
I_{DM}^*	Pulsed Drain Current	$V_{GS}=-10\text{V (P)}$	25	-20	
I_S^*	Diode Continuous Forward Current		2.5	-2.5	A
T_J	Maximum Junction Temperature	150		$^\circ\text{C}$	
T_{STG}	Storage Temperature Range	-55 to 150			
P_D^*	Power Dissipation	$T_A=25^\circ\text{C}$	2		W
		$T_A=100^\circ\text{C}$	0.8		
$R_{\theta JA}^*$	Thermal Resistance-Junction to Ambient	62.5		$^\circ\text{C/W}$	

Note : *Surface Mounted on 1in² pad area, $t \leq 10\text{sec}$.

Electrical Characteristics ($T_A = 25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Test Conditions	APM4568K			Unit	
			Min.	Typ.	Max.		
Static Characteristics							
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{GS}=0\text{V}, I_{DS}=250\mu\text{A}$	N-Ch	40	-	-	V
		$V_{GS}=0\text{V}, I_{DS}=-250\mu\text{A}$	P-Ch	-40	-	-	
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=32\text{V}, V_{GS}=0\text{V}$ $T_J=85^\circ\text{C}$	N-Ch	-	-	1	μA
			P-Ch	-	-	-1	
		$V_{DS}=-32\text{V}, V_{GS}=0\text{V}$ $T_J=85^\circ\text{C}$	N-Ch	-	-	30	
			P-Ch	-	-	-30	
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_{DS}=250\mu\text{A}$	N-Ch	1.3	2	2.5	V
		$V_{DS}=V_{GS}, I_{DS}=-250\mu\text{A}$	P-Ch	-1.3	-1.9	-2.5	
I_{GSS}	Gate Leakage Current	$V_{GS}=\pm 20\text{V}, V_{DS}=0\text{V}$	N-Ch	-	-	± 100	nA
		$V_{GS}=\pm 20\text{V}, V_{DS}=0\text{V}$	P-Ch	-	-	± 100	
$R_{DS(ON)}^a$	Drain-Source On-State Resistance	$V_{GS}=10\text{V}, I_{DS}=6.5\text{A}$	N-Ch	-	20	28	m Ω
		$V_{GS}=-10\text{V}, I_{DS}=-5\text{A}$	P-Ch	-	35	48	
		$V_{GS}=4.5\text{V}, I_{DS}=4.5\text{A}$	N-Ch	-	28	42	
		$V_{GS}=-4.5\text{V}, I_{DS}=-3\text{A}$	P-Ch	-	48	68	

Electrical Characteristics (Cont.) (T_A = 25°C unless otherwise noted)

Symbol	Parameter	Test Conditions	APM4568K			Unit	
			Min.	Typ.	Max.		
Diode Characteristics							
V _{SD} ^a	Diode Forward Voltage	I _{SD} =2A, V _{GS} =0V	N-Ch	-	0.8	1.1	V
		I _{SD} =-2A, V _{GS} =0V	P-Ch	-	-0.8	-1.1	
Dynamic Characteristics^b							
R _G	Gate Resistance	V _{GS} =0V, V _{DS} =0V, F=1MHz	N-Ch	-	2	-	Ω
			P-Ch	-	8	-	
C _{iss}	Input Capacitance	N-Channel V _{GS} =0V, V _{DS} =20V, Frequency=1.0MHz P-Channel V _{GS} =0V, V _{DS} =-20V, Frequency=1.0MHz	N-Ch	-	980	-	pF
C _{oss}	Output Capacitance		P-Ch	-	1095	-	
			N-Ch	-	110	-	
C _{rss}	Reverse Transfer Capacitance		P-Ch	-	125	-	
		N-Ch	-	75	-		
t _{d(ON)}	Turn-on Delay Time	N-Channel V _{DD} =20V, R _L =20Ω, I _{DS} =1A, V _{GEN} =10V, R _G =6Ω P-Channel V _{DD} =-20V, R _L =20Ω, I _{DS} =-1A, V _{GEN} =-10V, R _G =6Ω	N-Ch	-	16	30	ns
			P-Ch	-	12	23	
T _r	Turn-on Rise Time		N-Ch	-	19	35	
			P-Ch	-	21	39	
t _{d(OFF)}	Turn-off Delay Time		N-Ch	-	30	55	
			P-Ch	-	43	78	
T _f	Turn-off Fall Time	N-Ch	-	6	12		
		P-Ch	-	11	21		
t _{rr}	Reverse Recovery Time	N-Channel I _{SD} =6.5A, dI _{SD} /dt = 100A/μs	N-Ch	-	20	-	ns
			P-Ch	-	19	-	
Q _{rr}	Reverse Recovery Charge	P-Channel I _{SD} =-5A, dI _{SD} /dt = 100A/μs	N-Ch	-	14	-	nC
			P-Ch	-	12	-	
Gate Charge Characteristics^b							
Q _g	Total Gate Charge	N-Channel V _{DS} =20V, V _{GS} =10V, I _{DS} =6.5A	N-Ch	-	20	28	nC
			P-Ch	-	20	28	
Q _{gs}	Gate-Source Charge	P-Channel V _{DS} =-20V, V _{GS} =-10V, I _{DS} =-5A	N-Ch	-	3	-	
			P-Ch	-	3.5	-	
Q _{gd}	Gate-Drain Charge		N-Ch	-	6	-	
			P-Ch	-	3.5	-	

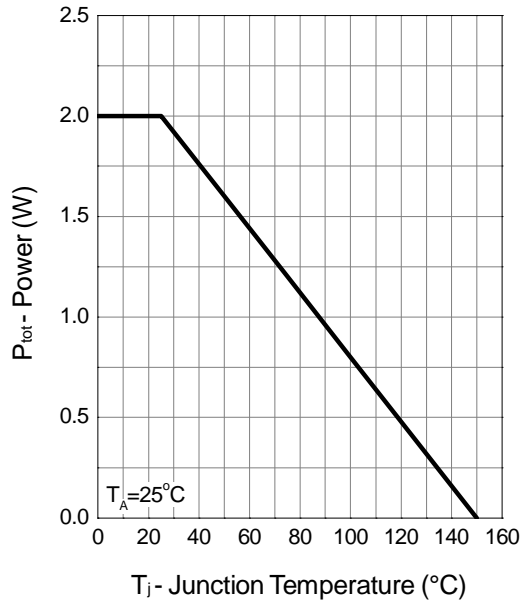
Note a : Pulse test ; pulse width ≤ 300ms, duty cycle ≤ 2%.

Note b : Guaranteed by design, not subject to production testing.

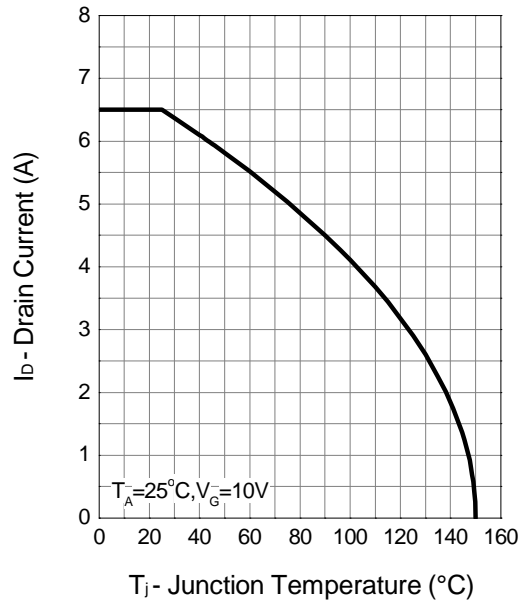
Typical Operating Characteristics

N-Channel

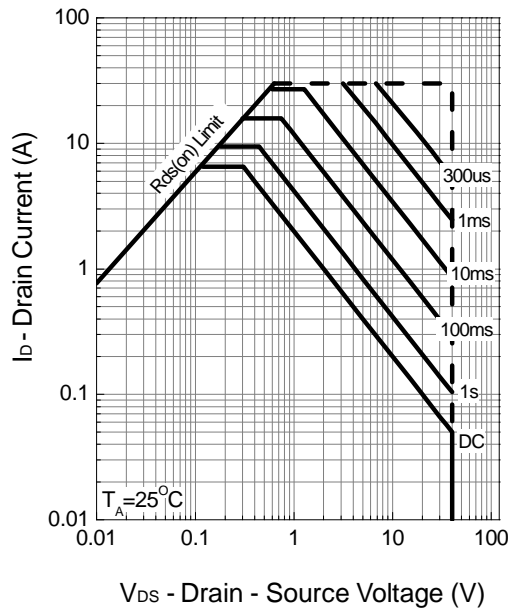
Power Dissipation



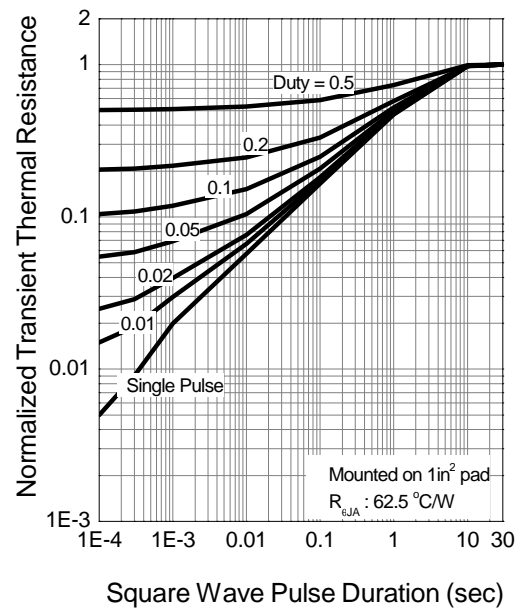
Drain Current



Safe Operation Area



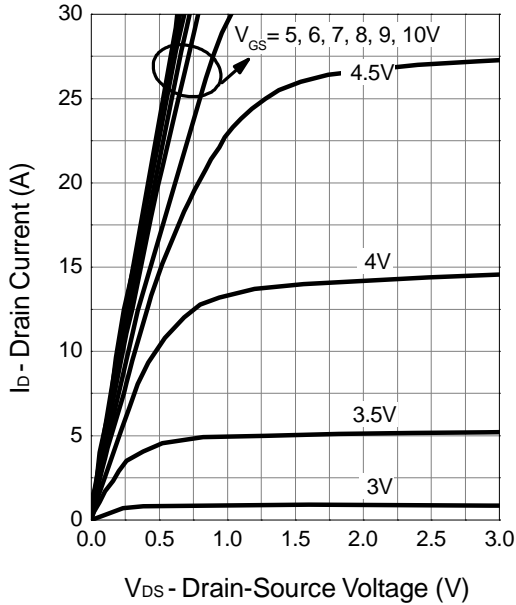
Thermal Transient Impedance



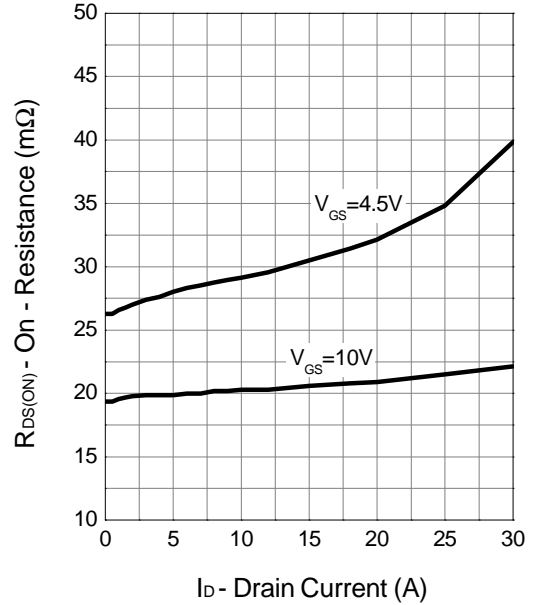
Typical Operating Characteristics (Cont.)

N-Channel

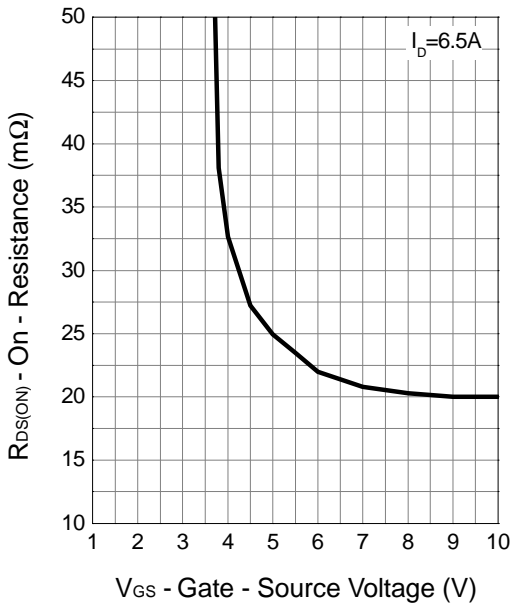
Output Characteristics



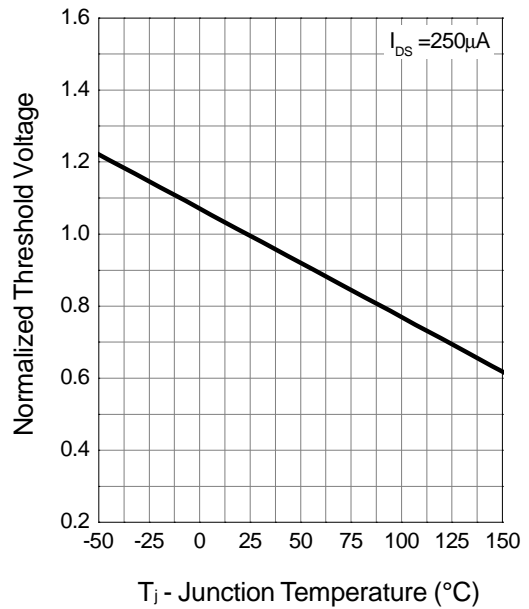
Drain-Source On Resistance



Drain-Source On Resistance



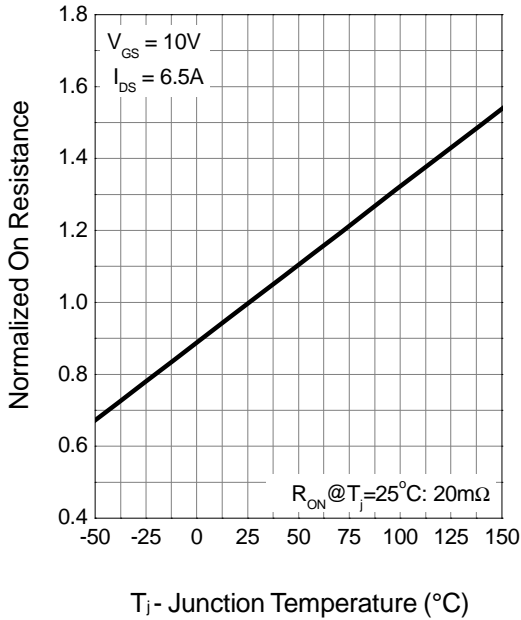
Gate Threshold Voltage



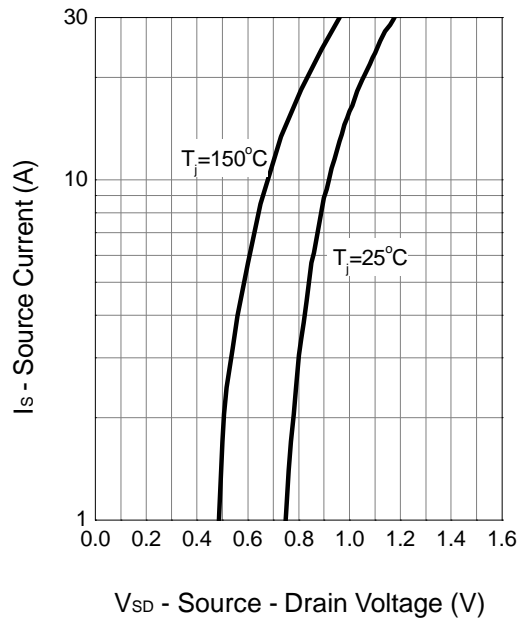
Typical Operating Characteristics (Cont.)

N-Channel

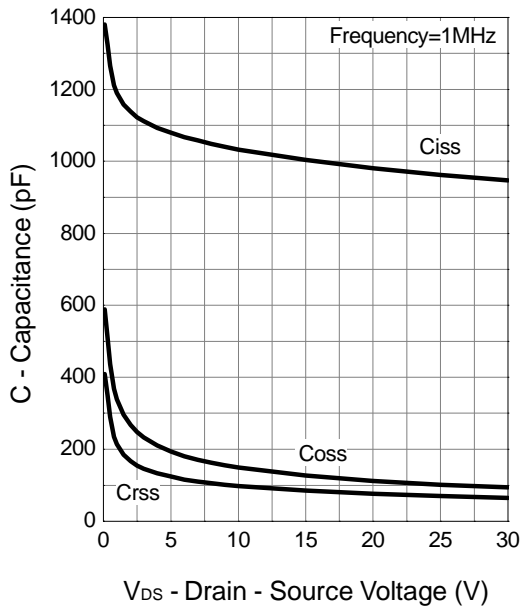
Drain-Source On Resistance



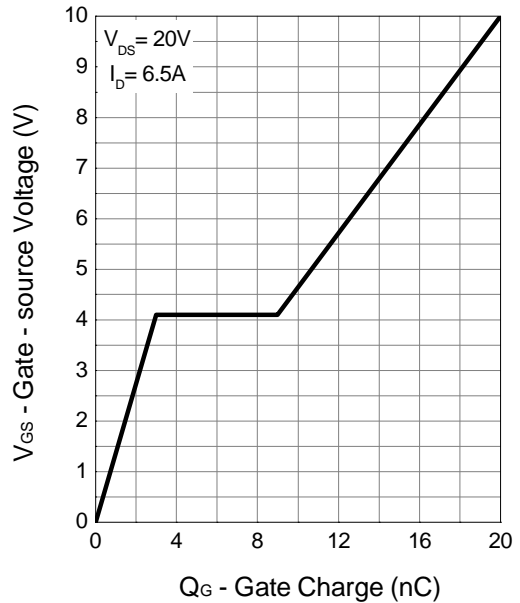
Source-Drain Diode Forward



Capacitance



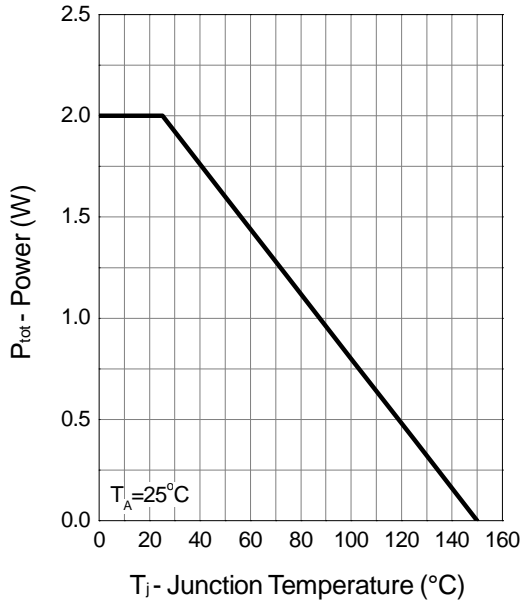
Gate Charge



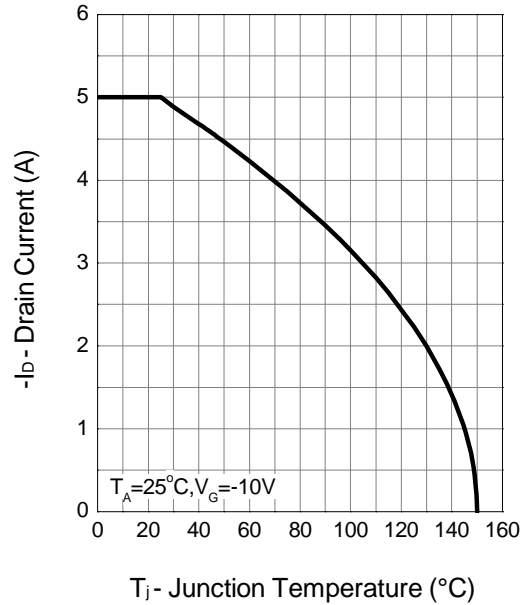
Typical Operating Characteristics (Cont.)

P-Channel

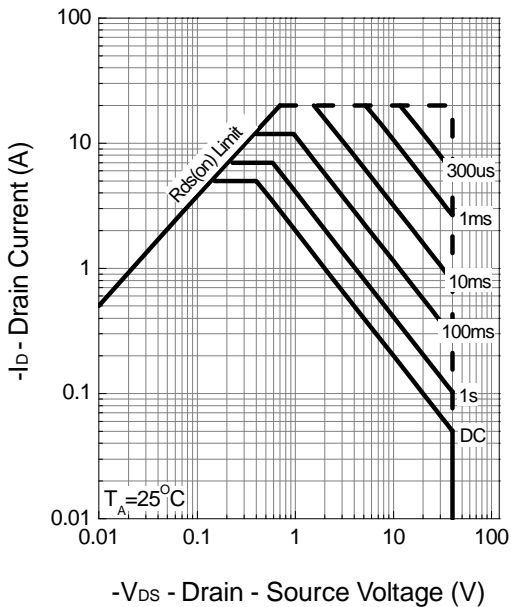
Power Dissipation



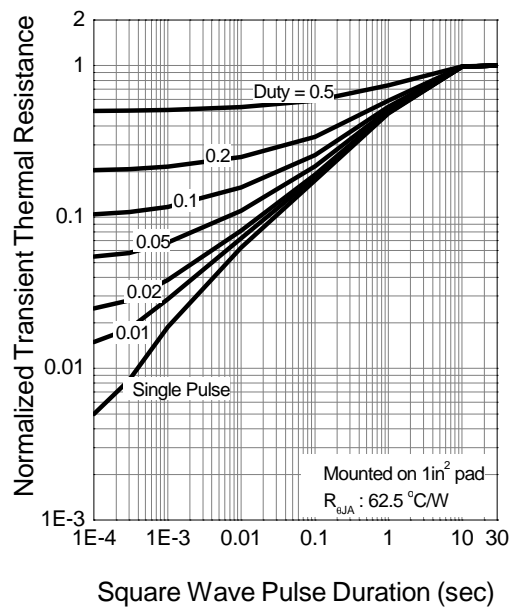
Drain Current



Safe Operation Area



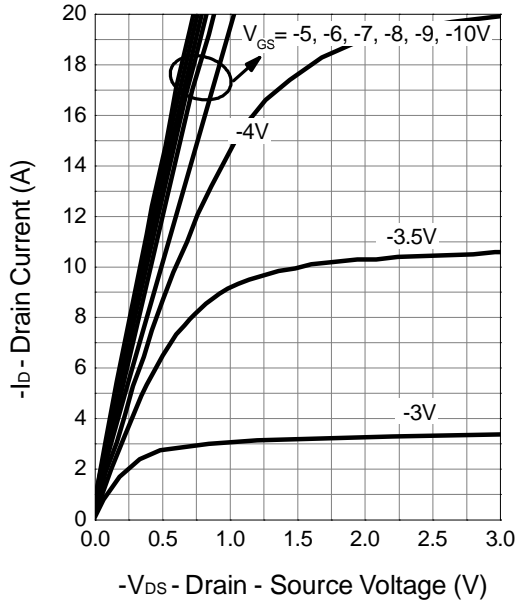
Thermal Transient Impedance



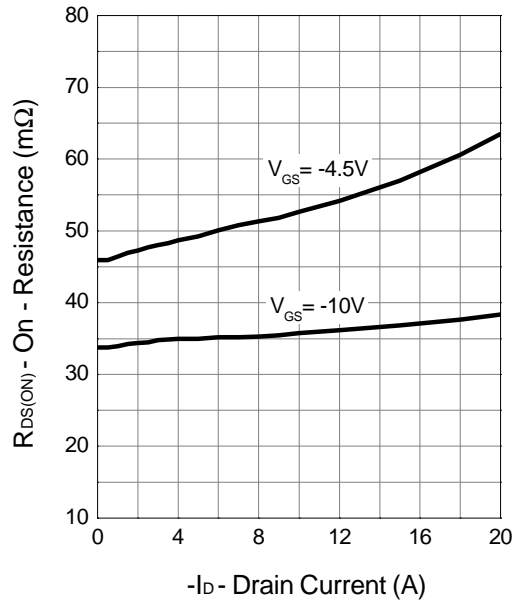
Typical Operating Characteristics (Cont.)

P-Channel

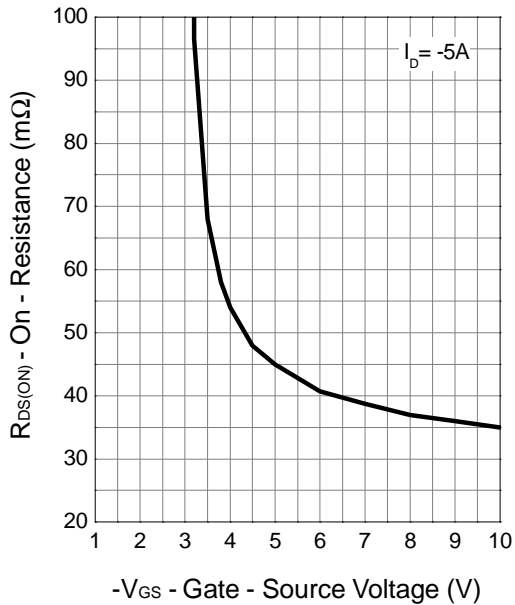
Output Characteristics



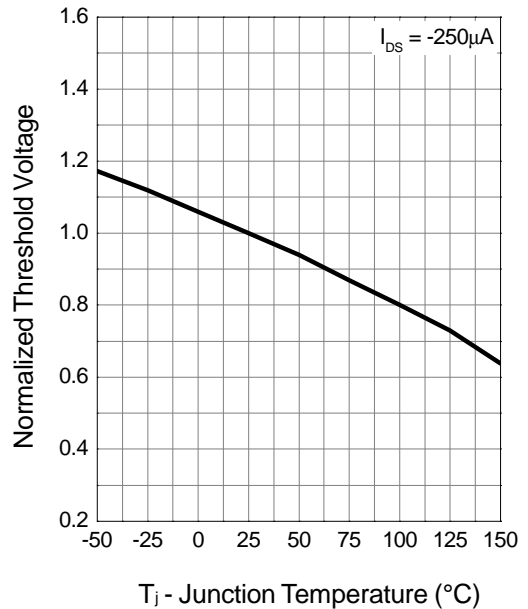
Drain-Source On Resistance



Drain-Source On Resistance



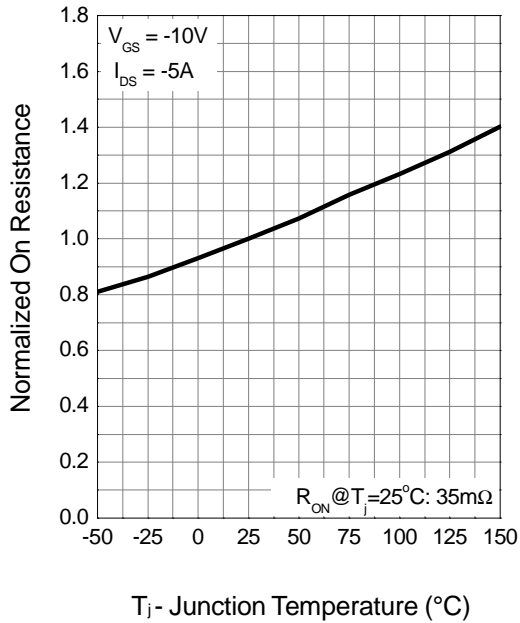
Gate Threshold Voltage



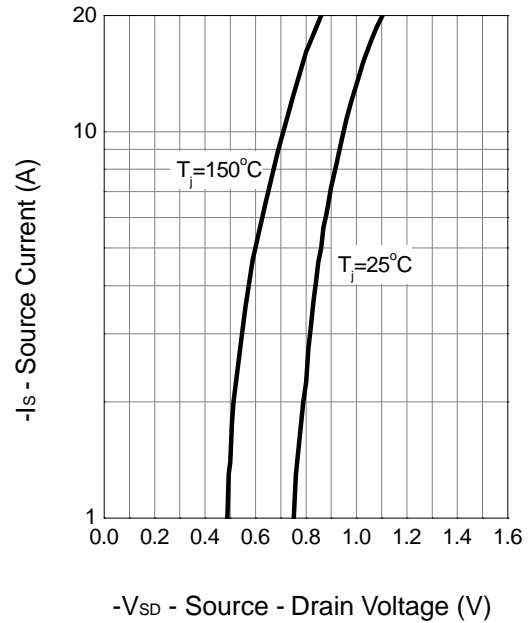
Typical Operating Characteristics (Cont.)

P-Channel

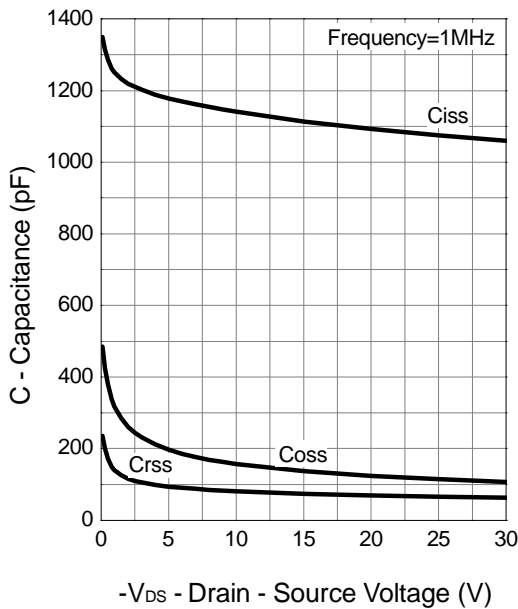
Drain-Source On Resistance



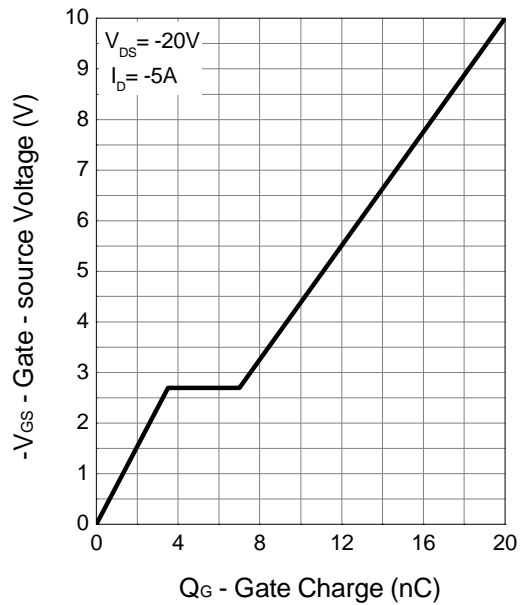
Source-Drain Diode Forward



Capacitance

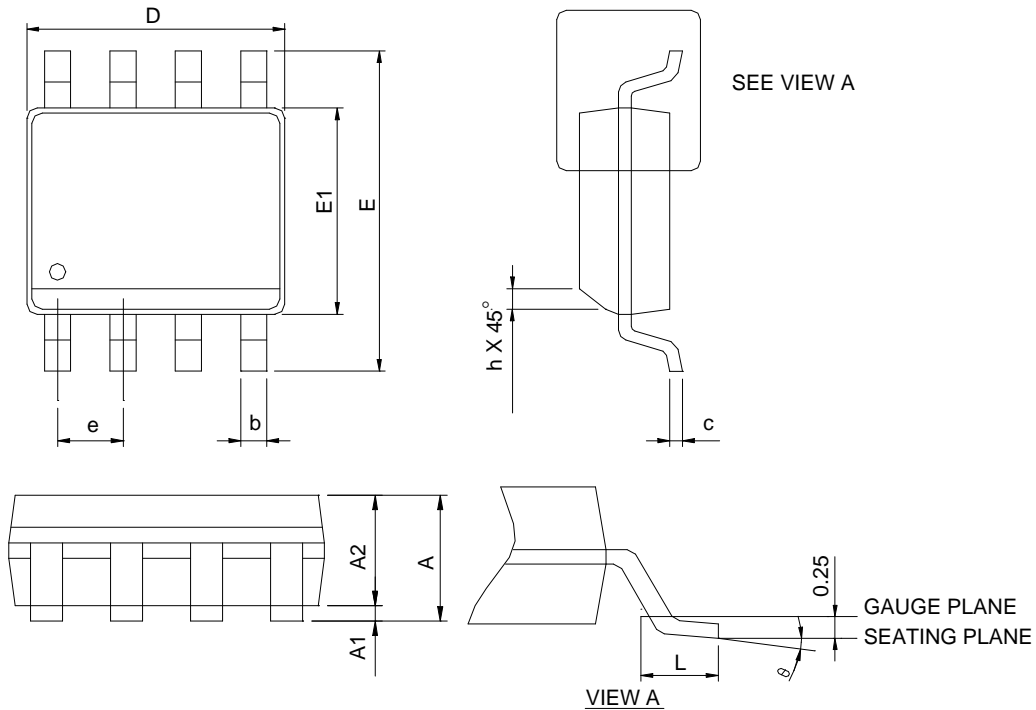


Gate Charge



Package Information

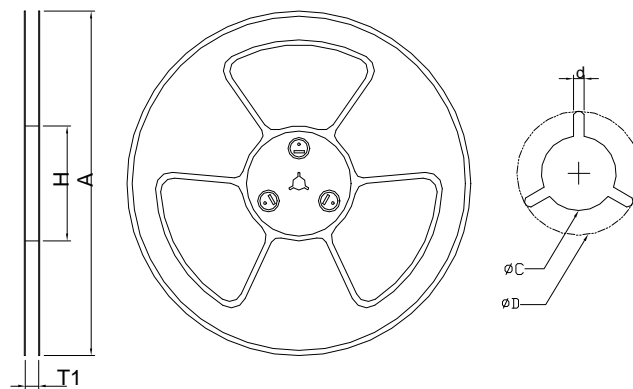
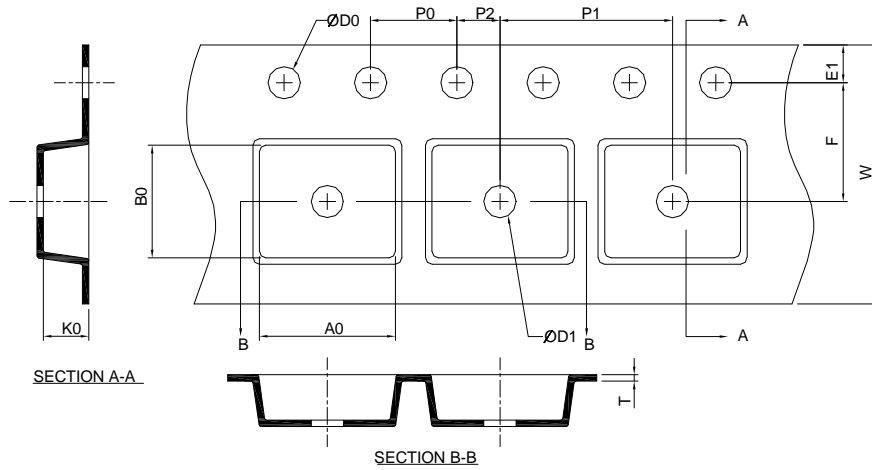
SOP-8



SYMBOL	SOP-8			
	MILLIMETERS		INCHES	
	MIN.	MAX.	MIN.	MAX.
A		1.75		0.069
A1	0.10	0.25	0.004	0.010
A2	1.25		0.049	
b	0.31	0.51	0.012	0.020
c	0.17	0.25	0.007	0.010
D	4.80	5.00	0.189	0.197
E	5.80	6.20	0.228	0.244
E1	3.80	4.00	0.150	0.157
e	1.27 BSC		0.050 BSC	
h	0.25	0.50	0.010	0.020
L	0.40	1.27	0.016	0.050
θ	0°	8°	0°	8°

- Note: 1. Follow JEDEC MS-012 AA.
 2. Dimension "D" does not include mold flash, protrusions or gate burrs. Mold flash, protrusion or gate burrs shall not exceed 6 mil per side.
 3. Dimension "E" does not include inter-lead flash or protrusions. Inter-lead flash and protrusions shall not exceed 10 mil per side.

Carrier Tape & Reel Dimensions



Application	A	H	T1	C	d	D	W	E1	F
SOP-8	330.0 ± 2.00	50 MIN.	12.4+2.00 -0.00	13.0+0.50 -0.20	1.5 MIN.	20.2 MIN.	12.0 ±0.30	1.75 ±0.10	5.5 ±0.05
	P0	P1	P2	D0	D1	T	A0	B0	K0
	4.0 ±0.10	8.0 ±0.10	2.0 ±0.05	1.5+0.10 -0.00	1.5 MIN.	0.6+0.00 -0.40	6.40 ±0.20	5.20 ±0.20	2.10 ±0.20

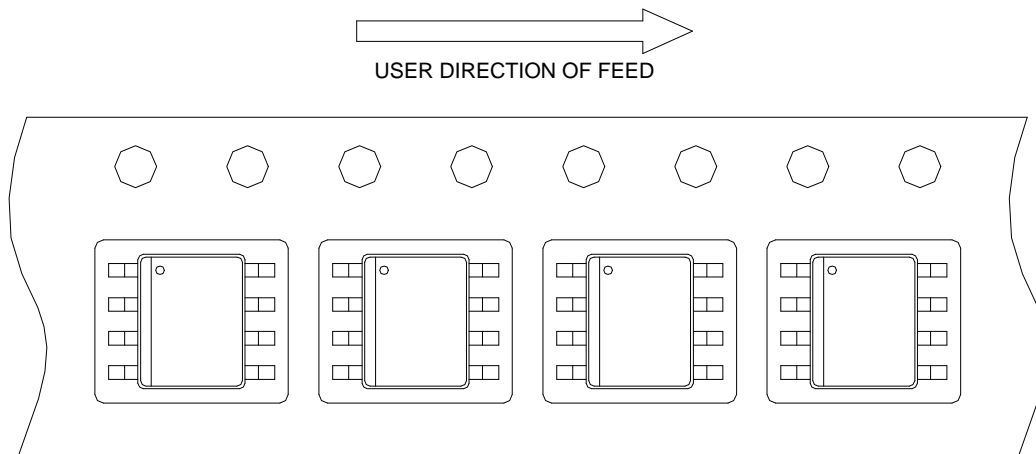
(mm)

Devices Per Unit

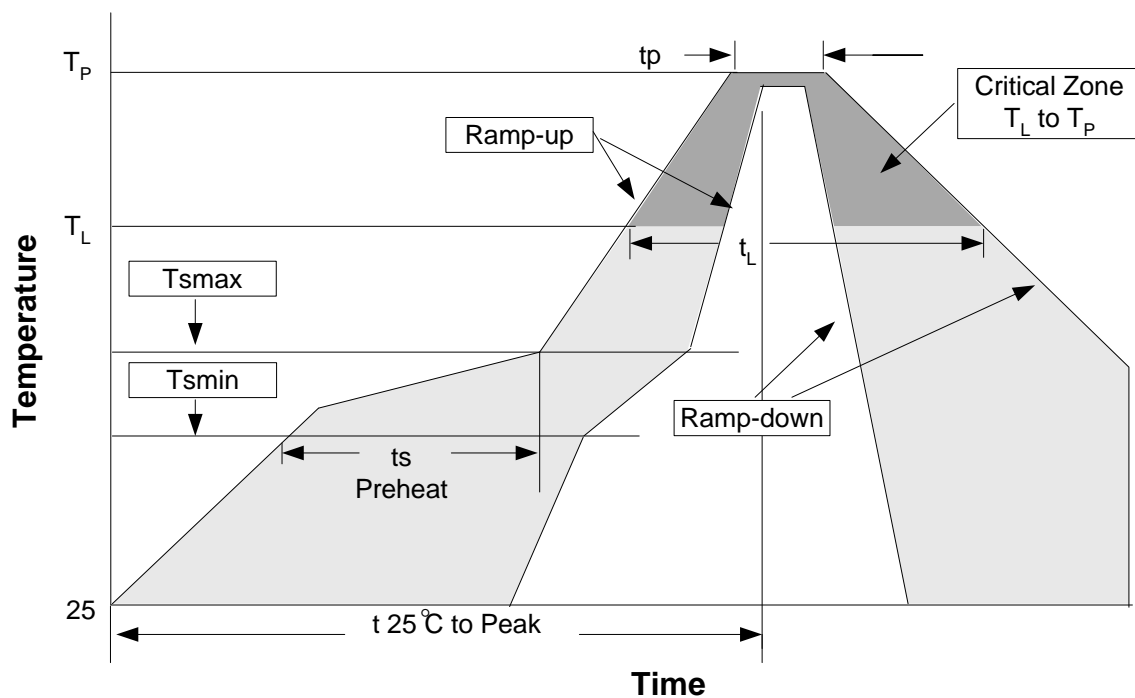
Package Type	Unit	Quantity
SOP-8	Tape & Reel	2500

Taping Direction Information

SOP-8



Reflow Condition (IR/Convection or VPR Reflow)



Reliability Test Program

Test item	Method	Description
SOLDERABILITY	MIL-STD-883D-2003	245°C, 5 sec
HOLT	MIL-STD-883D-1005.7	1000 Hrs Bias @ 125°C
PCT	JESD-22-B, A102	168 Hrs, 100%RH, 121°C
TST	MIL-STD-883D-1011.9	-65°C~150°C, 200 Cycles

Classification Reflow Profiles

Profile Feature	Sn-Pb Eutectic Assembly	Pb-Free Assembly
Average ramp-up rate (T _L to T _P)	3°C/second max.	3°C/second max.
Preheat		
- Temperature Min (T _{min})	100°C	150°C
- Temperature Max (T _{max})	150°C	200°C
- Time (min to max) (ts)	60-120 seconds	60-180 seconds
Time maintained above:		
- Temperature (T _L)	183°C	217°C
- Time (t _L)	60-150 seconds	60-150 seconds
Peak/Classification Temperature (T _p)	See table 1	See table 2
Time within 5°C of actual Peak Temperature (tp)	10-30 seconds	20-40 seconds
Ramp-down Rate	6°C/second max.	6°C/second max.
Time 25°C to Peak Temperature	6 minutes max.	8 minutes max.

Note: All temperatures refer to topside of the package. Measured on the body surface.

Table 1. SnPb Eutectic Process – Package Peak Reflow Temperatures

Package Thickness	Volume mm ³ <350	Volume mm ³ ≥350
<2.5 mm	240 +0/-5°C	225 +0/-5°C
≥2.5 mm	225 +0/-5°C	225 +0/-5°C

Table 2. Pb-free Process – Package Classification Reflow Temperatures

Package Thickness	Volume mm ³ <350	Volume mm ³ 350-2000	Volume mm ³ >2000
<1.6 mm	260 +0°C*	260 +0°C*	260 +0°C*
1.6 mm – 2.5 mm	260 +0°C*	250 +0°C*	245 +0°C*
≥2.5 mm	250 +0°C*	245 +0°C*	245 +0°C*

*Tolerance: The device manufacturer/supplier **shall** assure process compatibility up to and including the stated classification temperature (this means Peak reflow temperature +0°C. For example 260°C+0°C) at the rated MSL level.

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